

10680339_CLS
Most Frequently Occurring Classifications of Patents Returned
From A Search of 10680339 on April 15, 2004

Original Classifications

9 73/105
4 250/306
3 250/234
2 73/1.89
2 250/492.3

Cross-Reference Classifications

8 250/306
7 250/307
5 73/105
3 73/81
3 257/E29.322
2 250/216
2 250/234
2 250/492.2
2 369/126
2 438/48

Combined Classifications

14 73/105
12 250/306
7 250/307
5 250/234
3 73/81
3 250/216
3 250/492.2
3 250/492.3
3 257/E29.322
3 369/126
2 73/1.89
2 216/11
2 250/310
2 324/719
2 438/48

10680339_CLSTITLES

Titles of Most Frequently Occurring Classifications of Patents Returned

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14	73/105	(9 OR, 5 XR)
	Class 073 :	MEASURING AND TESTING
	73/104	SURFACE AND CUTTING EDGE TESTING
	73/105	.Roughness
12	250/306	(4 OR, 8 XR)
	Class 250 :	RADIANT ENERGY
	250/306	INSPECTION OF SOLIDS OR LIQUIDS BY CHARGED PARTICLES
7	250/307	(0 OR, 7 XR)
	Class 250 :	RADIANT ENERGY
	250/306	INSPECTION OF SOLIDS OR LIQUIDS BY CHARGED PARTICLES
	250/307	.Methods
5	250/234	(3 OR, 2 XR)
	Class 250 :	RADIANT ENERGY
	250/200	PHOTOCELLS; CIRCUITS AND APPARATUS
	250/216	.Optical or pre-photocell system
	250/234	..Means for moving optical system
3	73/81	(0 OR, 3 XR)
	Class 073 :	MEASURING AND TESTING
	73/78	HARDNESS
	73/81	.By penetrator or indenter
3	250/216	(1 OR, 2 XR)
	Class 250 :	RADIANT ENERGY
	250/200	PHOTOCELLS; CIRCUITS AND APPARATUS
	250/216	.Optical or pre-photocell system
3	250/492.2	(1 OR, 2 XR)
	Class 250 :	RADIANT ENERGY
	250/492.1	IRRADIATION OF OBJECTS OR MATERIAL
	250/492.2	.Irradiation of semiconductor devices
3	250/492.3	(2 OR, 1 XR)
	Class 250 :	RADIANT ENERGY
	250/492.1	IRRADIATION OF OBJECTS OR MATERIAL
	250/492.3	.Ion or electron beam irradiation
3	257/E29.322	(0 OR, 3 XR)

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Class 257 : ACTIVE SOLID-STATE DEVICES

257/E29.162Insulating materials for IGFET (EPO)

257/E29.166 .Types of semiconductor device (EPO)

257/E29.169 ..Controllable by only signal applied to
control electrode (e.g., base of bipolar
transistor, gate
of field-effect transistor) (EPO)

257/E29.226 ...Unipolar device (EPO)

257/E29.322Single electron transistors: Coulomb
blockade device (EPO)

3 369/126 (1 OR, 2 XR)

Class 369 : DYNAMIC INFORMATION STORAGE OR RETRIEVAL

369/99 SPECIFIC DETAIL OF INFORMATION HANDLING PORTIO

N

OF SYSTEM

369/126 .Electrical modification or sensing of storage
medium (e.g., capacitive, resistive, electr
ostatic charge)

2 73/1.89 (2 OR, 0 XR)

Class 073 : MEASURING AND TESTING

73/1.01 INSTRUMENT PROVING OR CALIBRATING

73/1.89 .Roughness or hardness

2 216/11 (1 OR, 1 XR)

Class 216 : ETCHING A SUBSTRATE: PROCESSES

216/11 FORMING OR TREATING AN ARTICLE WHOSE FINAL
CONFIGURATION HAS A PROJECTION

2 250/310 (1 OR, 1 XR)

Class 250 : RADIANT ENERGY

250/306 INSPECTION OF SOLIDS OR LIQUIDS BY CHARGED
PARTICLES

250/310 .Electron probe type

2 324/719 (1 OR, 1 XR)

Class 324 : ELECTRICITY: MEASURING AND TESTING

324/600 IMPEDANCE, ADMITTANCE OR OTHER QUANTITIES
REPRESENTATIVE OF ELECTRICAL STIMULUS/RE

SPONSE

RELATIONSHIPS

324/649 .Lumped type parameters

324/691 ..Using resistance or conductance measurement

324/719 ...With semiconductor or IC materials quality
determination using conductivity effects

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2 438/48 (0 OR, 2 XR)
Class 438 : SEMICONDUCTOR DEVICE MANUFACTURING: PROCESS
438/48 MAKING DEVICE OR CIRCUIT RESPONSIVE TO
NONELECTRICAL SIGNAL